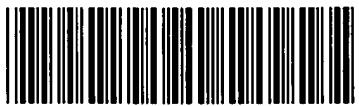


<b>Search Notes</b>	Application/Control No.	Applicant(s)/Patent Under Reexamination
	10826090	CHEN, SHI-SHIEN
	Examiner	Art Unit
	Neway, Samuel G	2626

### SEARCHED

Class	Subclass	Date	Examiner
704	8 (with text)	01/22/08	SN
341	50-107 (with text)	01/31/08	SN

### SEARCH NOTES

Search Notes	Date	Examiner
EAST: Text, Assignee, Inventor, Forward & Backward, and PLUS Search	08/14/07	SN
Consulted: P. Edouard	08/14/07	SN
Consulted: T. Smits	08/15/07	SN
Updated EAST Search	01/22/08	SN
STIC Search	01/30/08	SN
Consulted: P. Harper	01/29/08	SN

### INTERFERENCE SEARCH

Class	Subclass	Date	Examiner